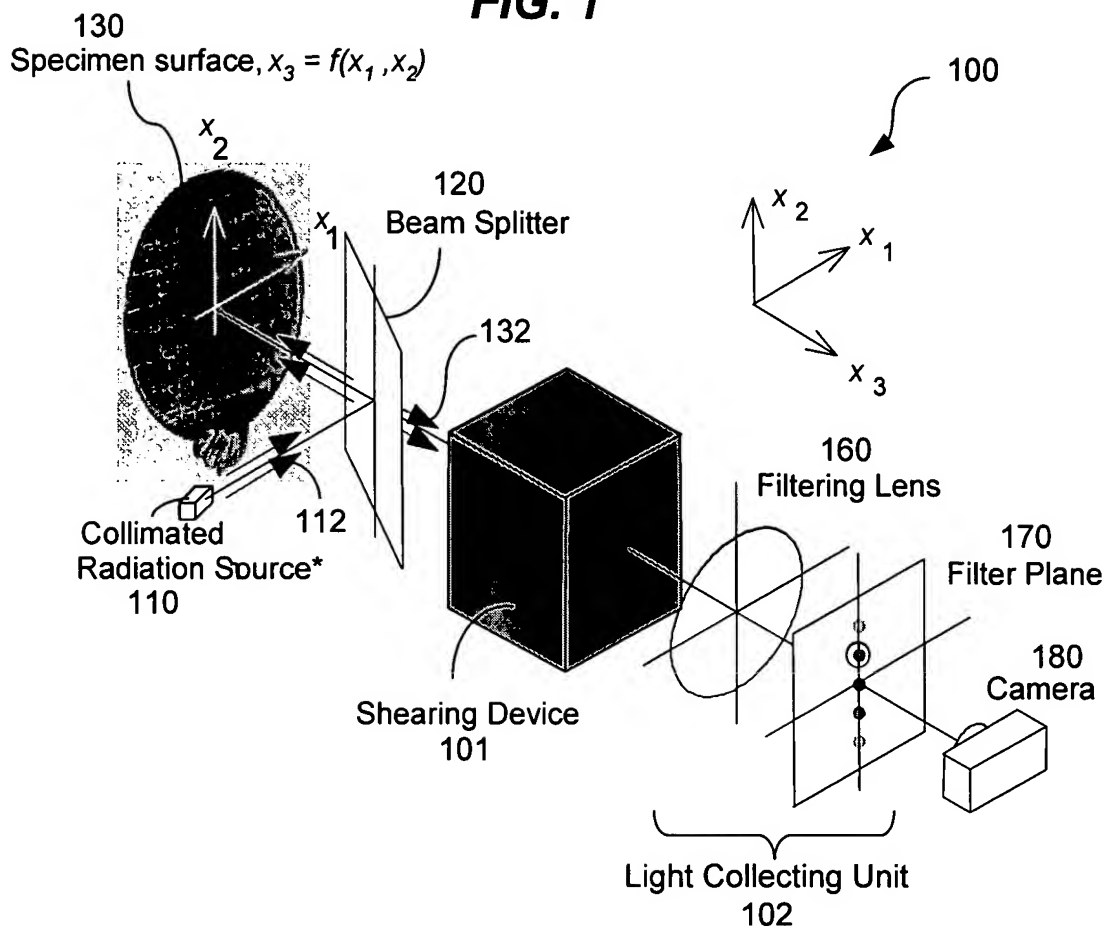
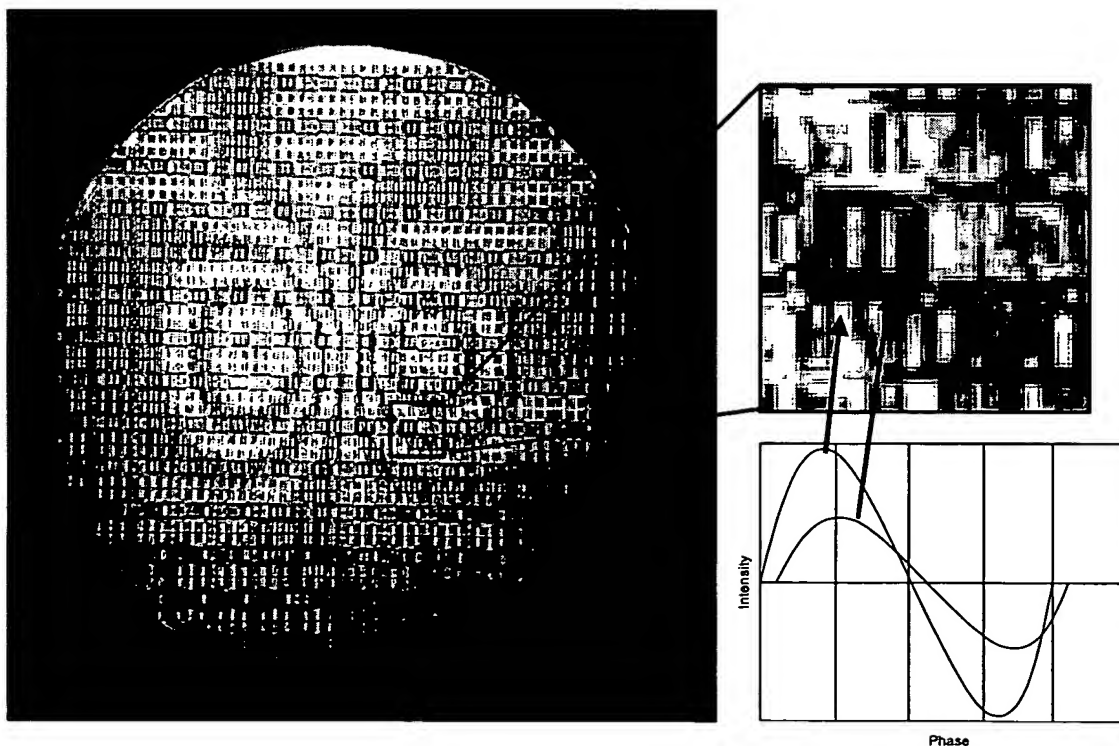
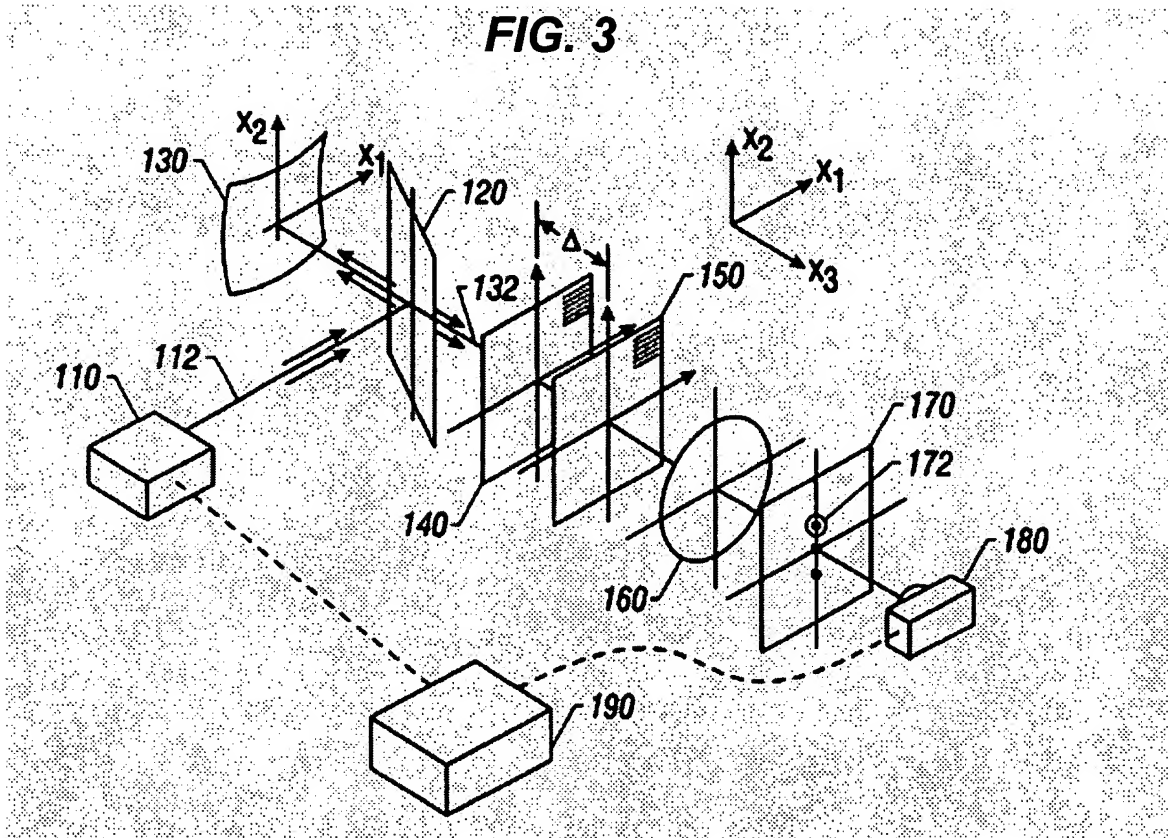
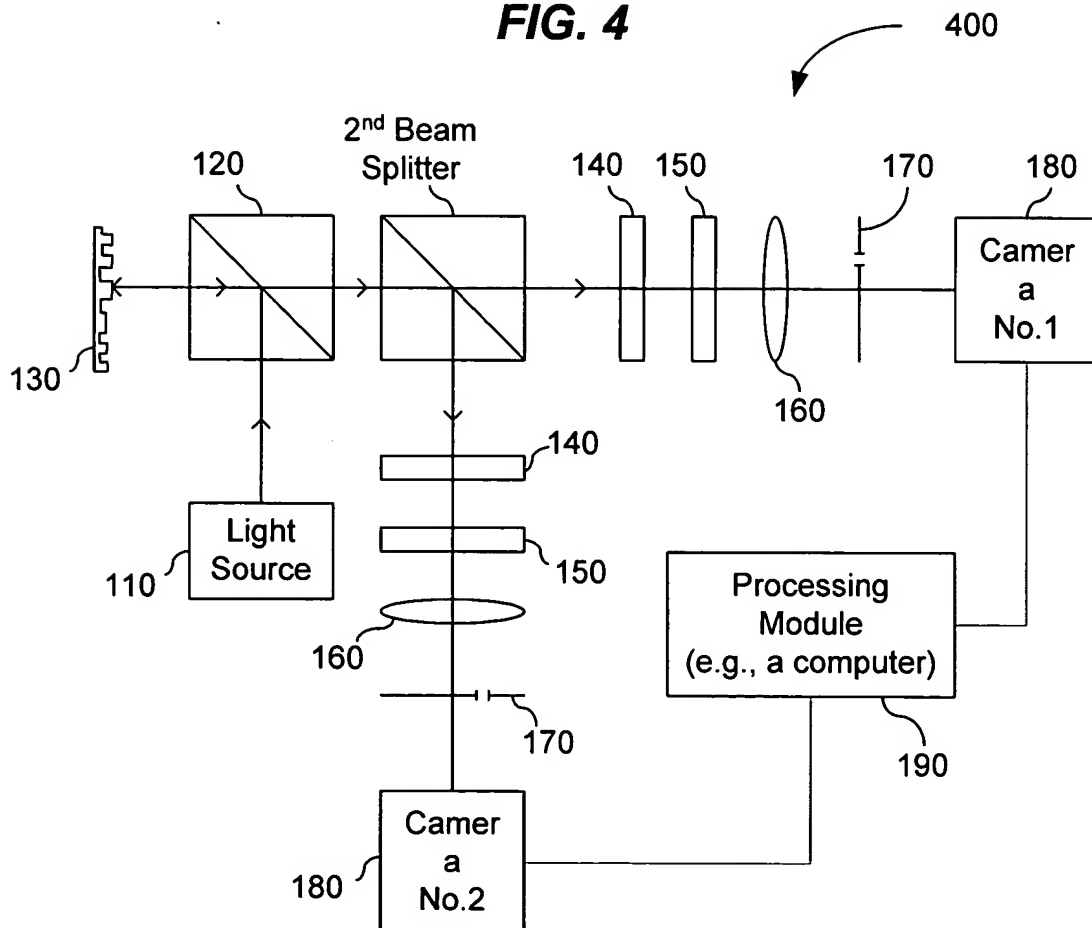
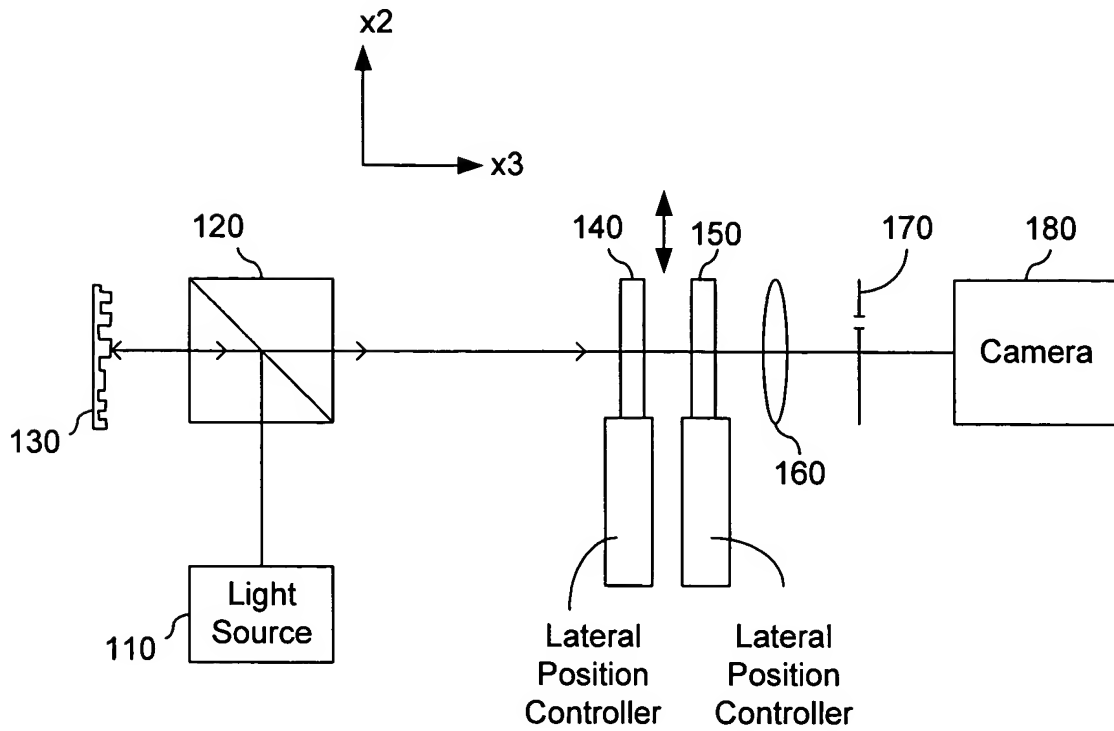
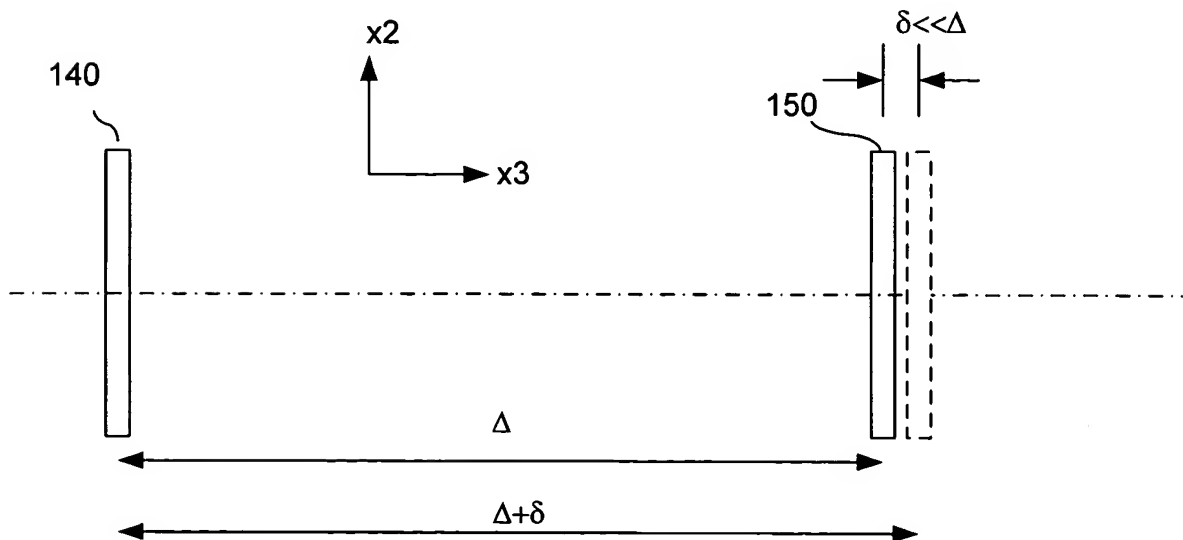


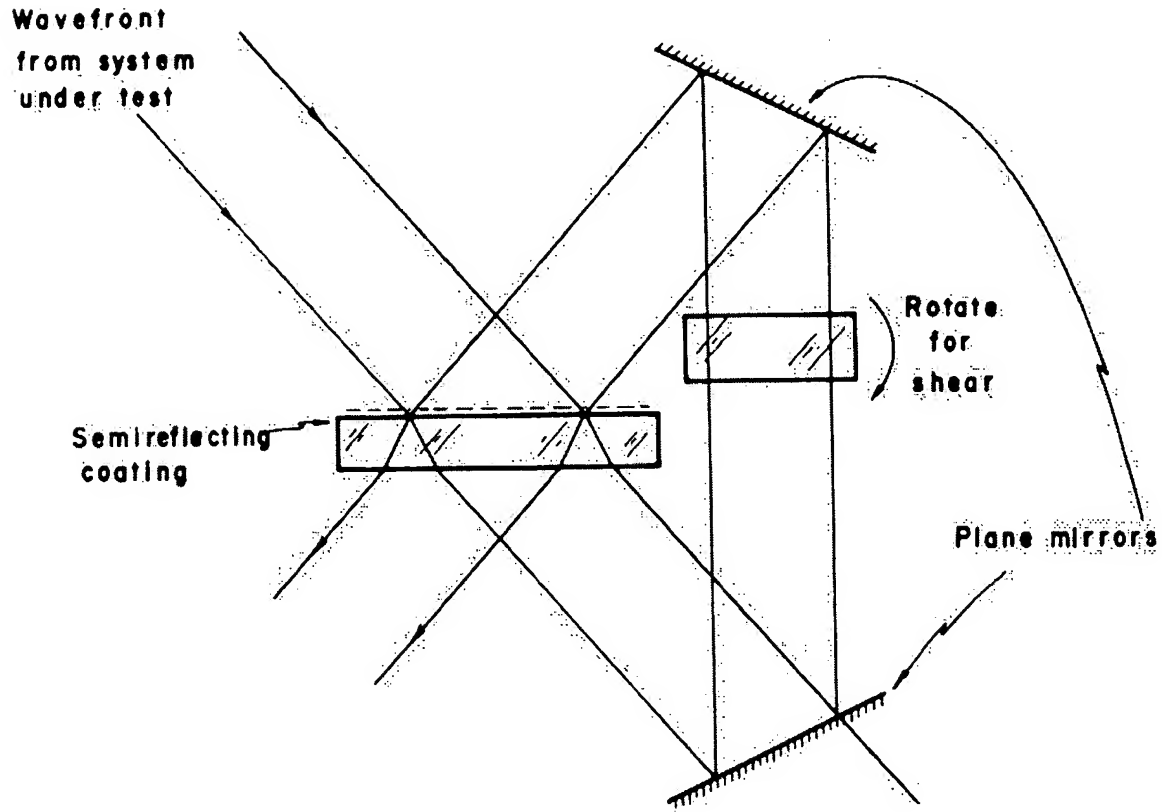
**FIG. 1****FIG. 2**

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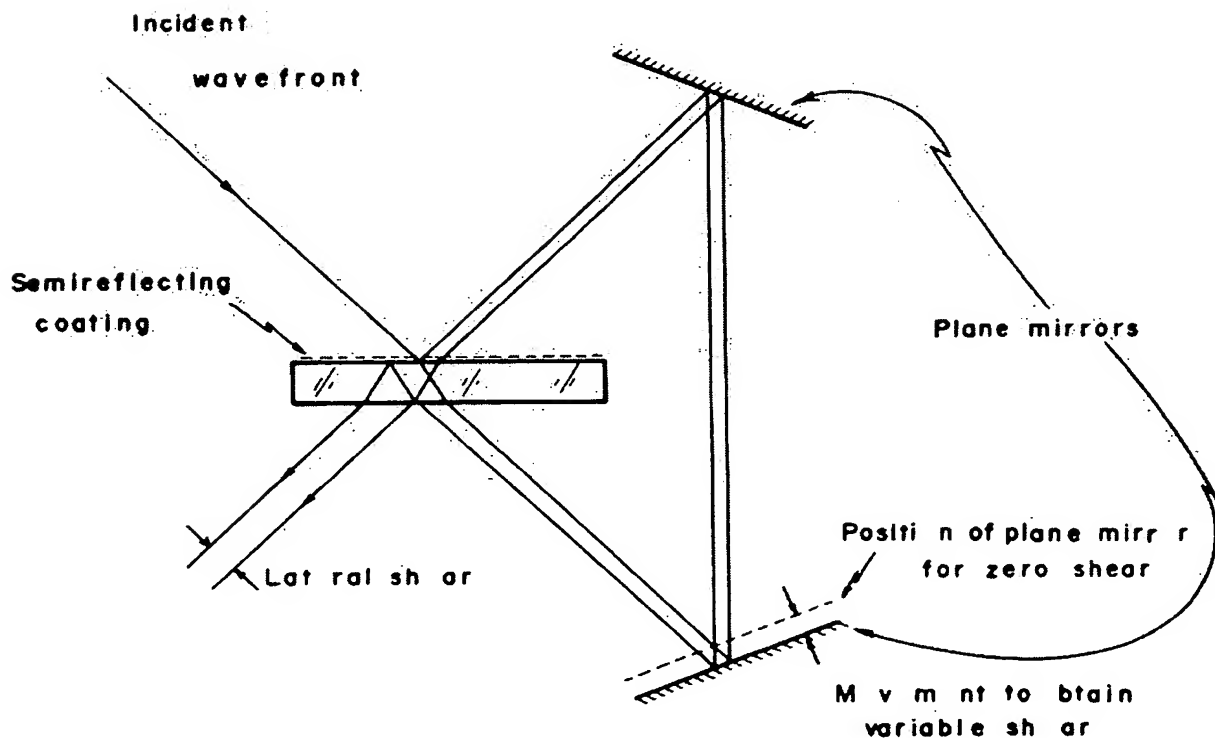
**FIG. 3****FIG. 4**

**FIG. 5A****FIG. 5B**

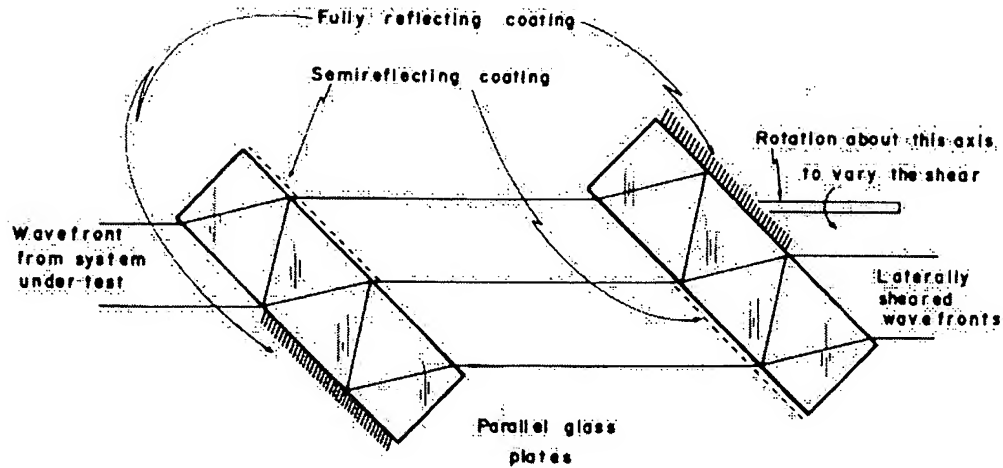
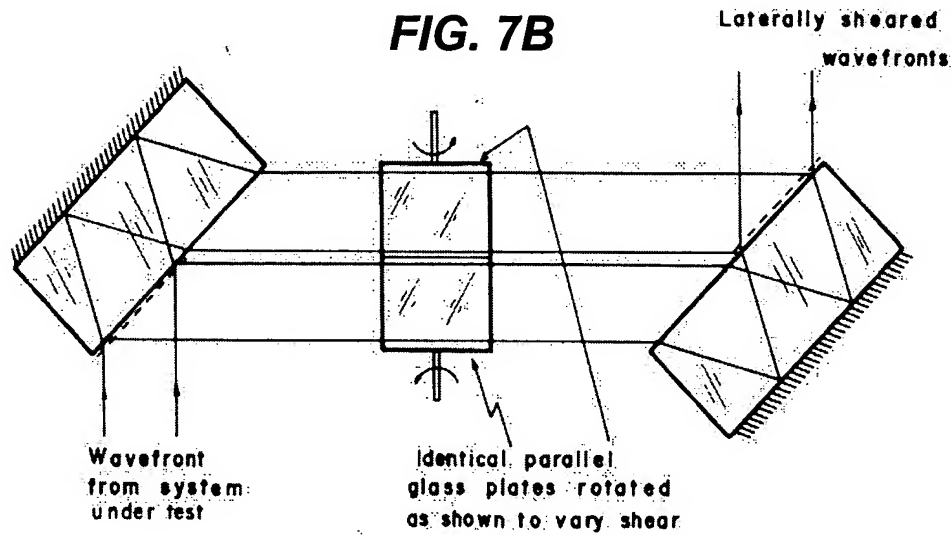
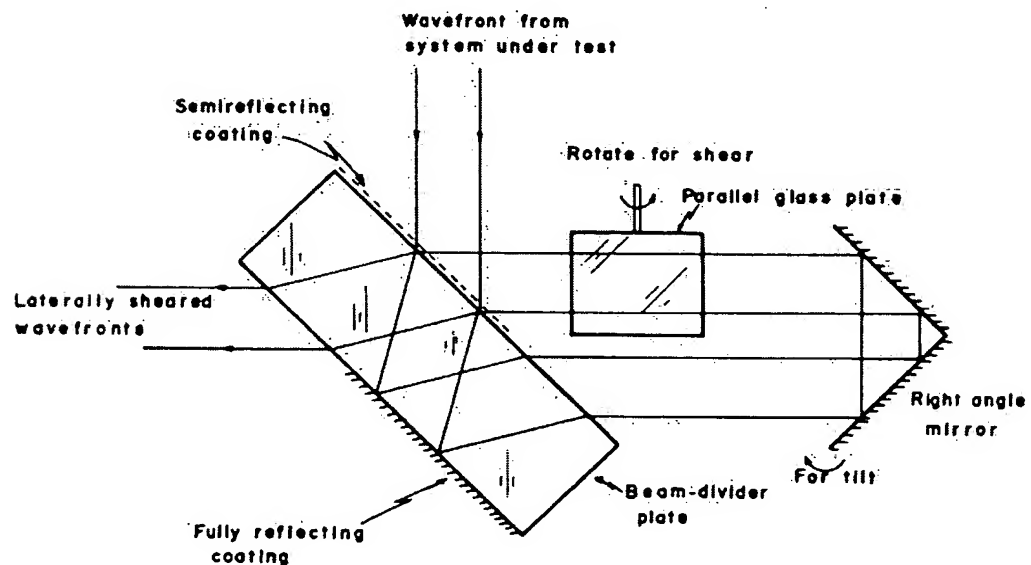
**FIG. 6A**



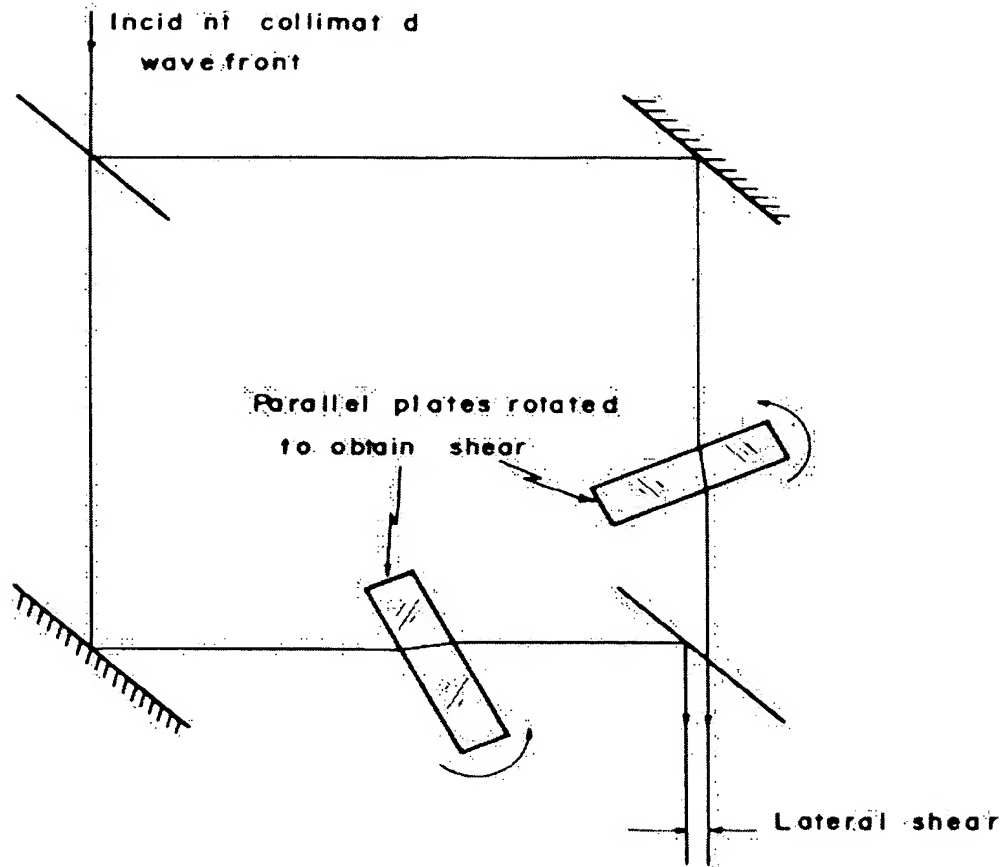
**FIG. 6B**



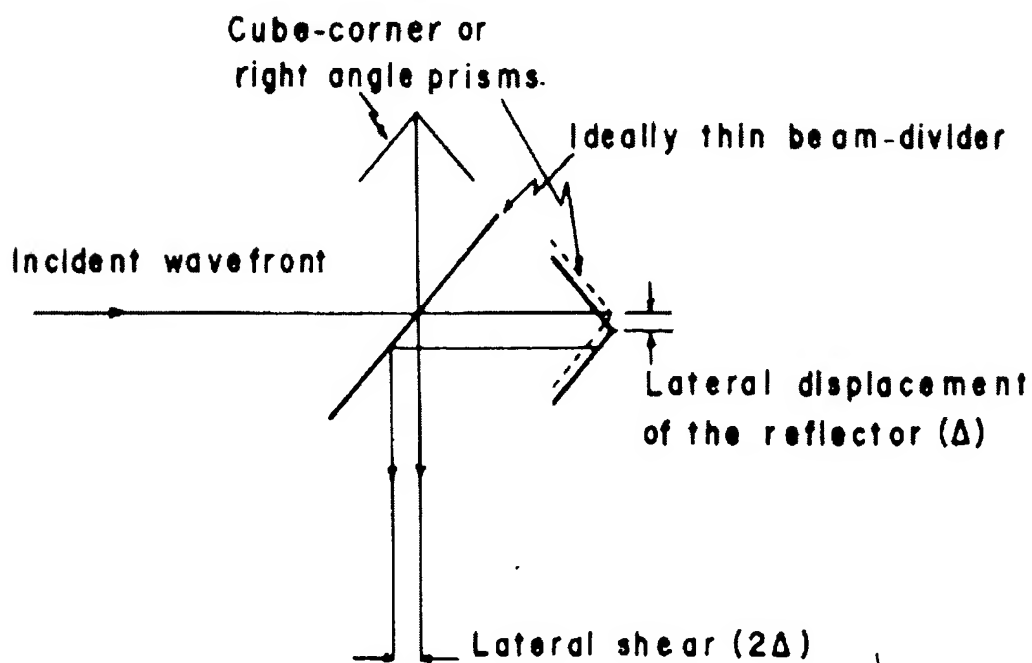
Applicant(s): Ares Rosakis et al.

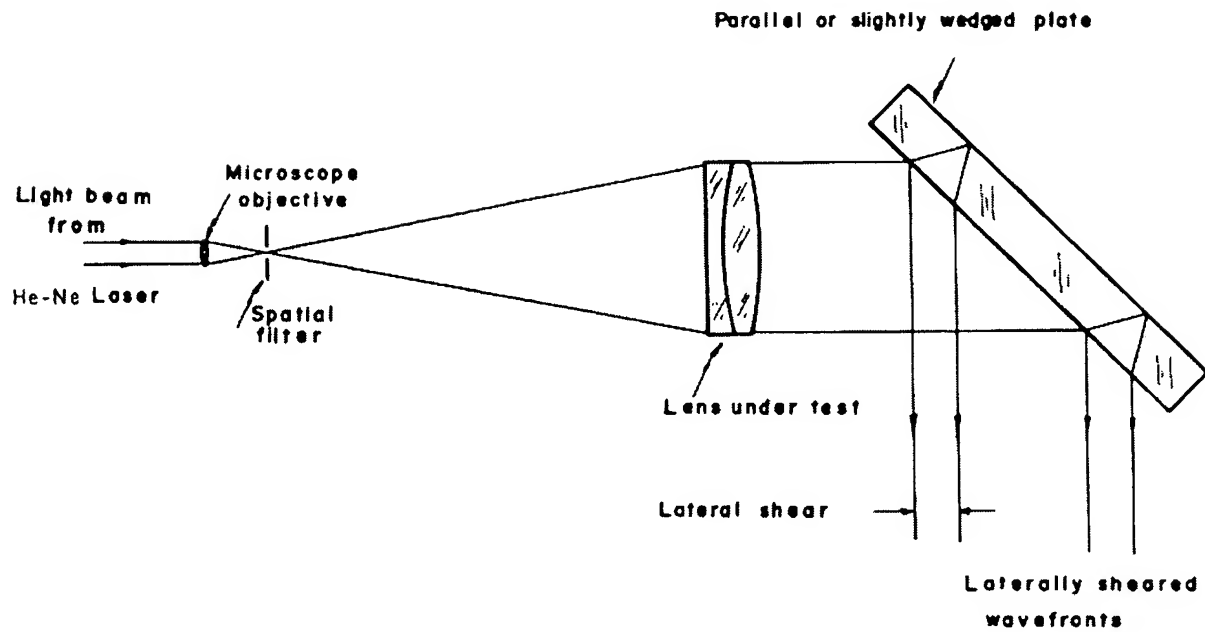
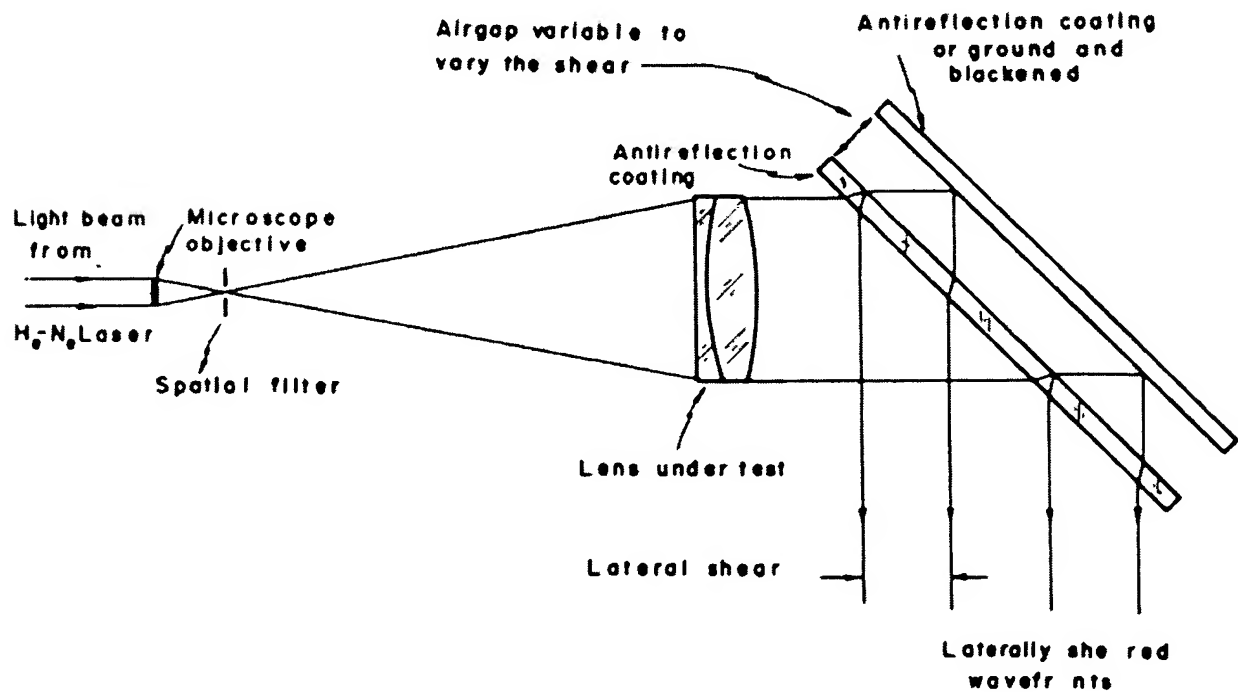
FULL-FIELD OPTICAL MEASUREMENTS OF SURFACE  
PROPERTIES OF PANELS, SUBSTRATES AND WAFERS**FIG. 7A****FIG. 7B****FIG. 7C**

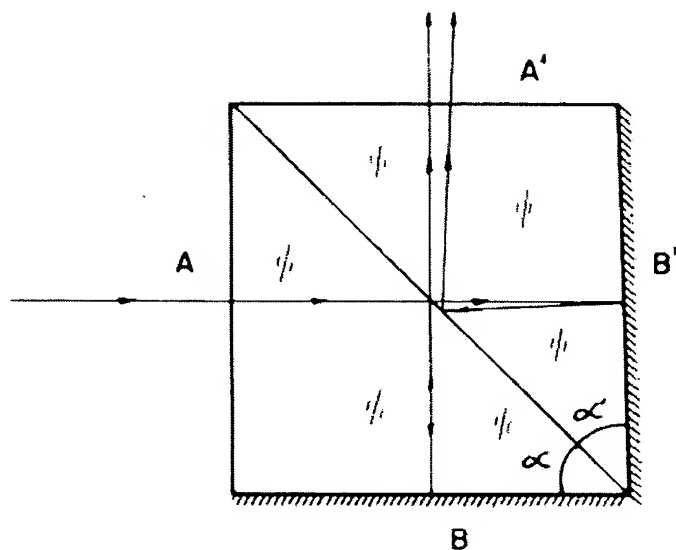
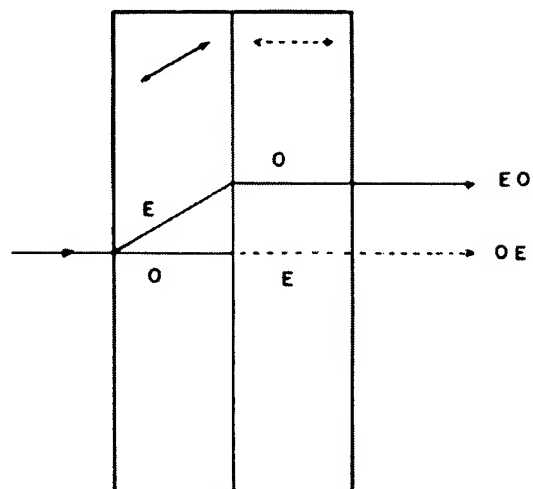
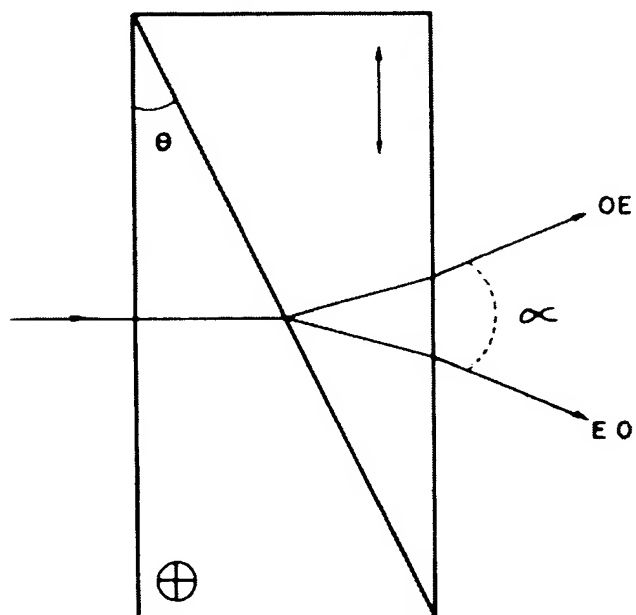
**FIG. 8**



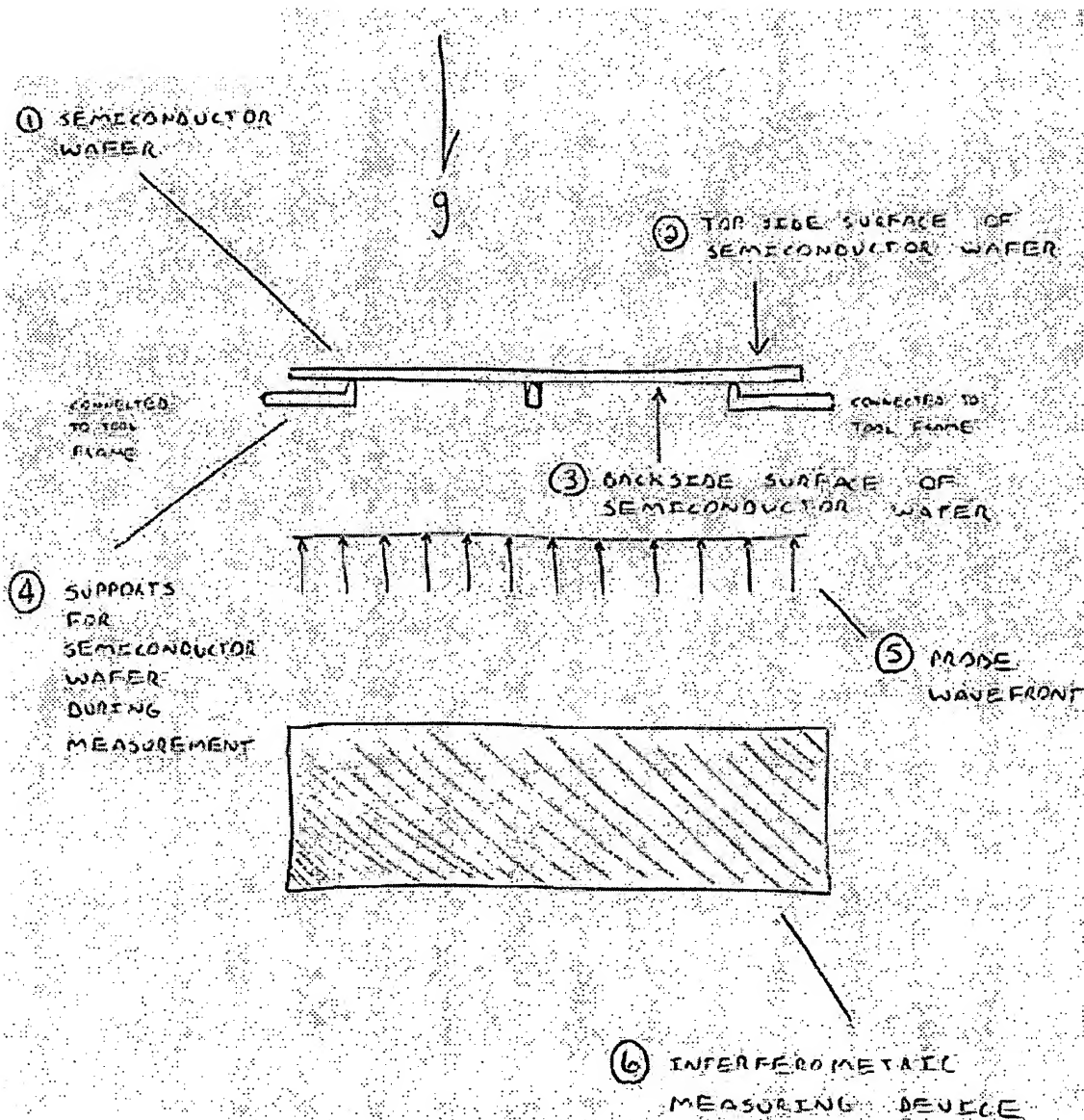
**FIG. 9**



**FIG. 10A****FIG. 10B**

**FIG. 11A****FIG. 11B****FIG. 11C**



**FIG. 12**

**FIG. 13**